

Replication-based deterministic testing of 2-dimensional arrays with highly interrelated cells

Azad, Siavoosh Payandeh; Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes 21st IEEE International Symposium on Design and Diagnostics of Electronic Circuits and Systems : DDECS 2018 : Budapest, Hungary 25-27 April, 2018 : proceedings 2018 / p. 21-26 : ill <https://doi.org/10.1109/DDECS.2018.00011>